Investigation of Structural Phases in Mo_{1-x}W_xTe₂ in STEM

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The transition metal dichalcogenide (TMD) alloys, Mo_{1-x}W_xTe₂, can host various phases at different temperatures and compositions. For example, with x < 0.10, Mo_{1-x}W_xTe₂ can crystallize to a 1T' semimetal, 2H semiconductor and a Td phase at high (900 °C), room and low (250 K) temperatures, respectively [1]. Both the 1T' and Td phases in MoTe₂ have been identified as topologically nontrivial [2]. At room temperature, the crystal structure of the ternary system transforms from 1T' to Td as the W concentration (x) increases from 0 to 1 [1]. The various structural phases hosted by this TMD show promise for a variety of applications and, in particular, phase change memory devices. Disorder brought by composition fluctuations can play an important role in the performance of such devices. It is therefore necessary to understand the distribution of substitutional atoms in the Mo_{1-x}W_xTe₂ alloys. We characterized the concentration and the distribution of the W atoms in 2H M00.91W0.09Te2, as well as lattice defects, by using aberration-corrected scanning transmission electron microscopy (STEM) with atomic resolution. During the acquisitions of STEM images, it is probably inevitable that the high-energy electrons cause radiation damage to the samples, which introduces extra lattice defects, such as vacancies and dislocations. In the meantime, the W atoms can migrate into neighboring sites through interstitial sites or vacancies. These structural variations can be recorded sequentially using short image acquisition times, which results in noisy data. However, by using machine learning algorithms [3], we can analyze the trajectories of the moving atoms from the noisy datasets and deduce various physical properties of the system, potentially extrapolating backwards in time to the pristine configuration before any radiation damage. Such data analysis will make the STEM experiments more relevant for finding the spatial distribution of substitutional atoms in the pristine structure. In addition, composition fluctuations limit the phonon correlation length, which will affect the lifetime of charge carriers and heat dissipation. The phonon modes can be characterized locally by using vibrational electron energy loss spectroscopy (EELS) in STEM, which may provide insights into the relationship between composition fluctuations and phonon correlation length [4].





Figure 1. A STEM image of few-layered MoTe2.



Figure 2. A STEM image of few-layered Mo(1-x)Mo(x)Te2, where the nominal composition is about x = 0.09.

References

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- [2] Deng, K., Wan, G., Deng, P. et al. Nature Phys 12, (2016) 1105–1110.
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